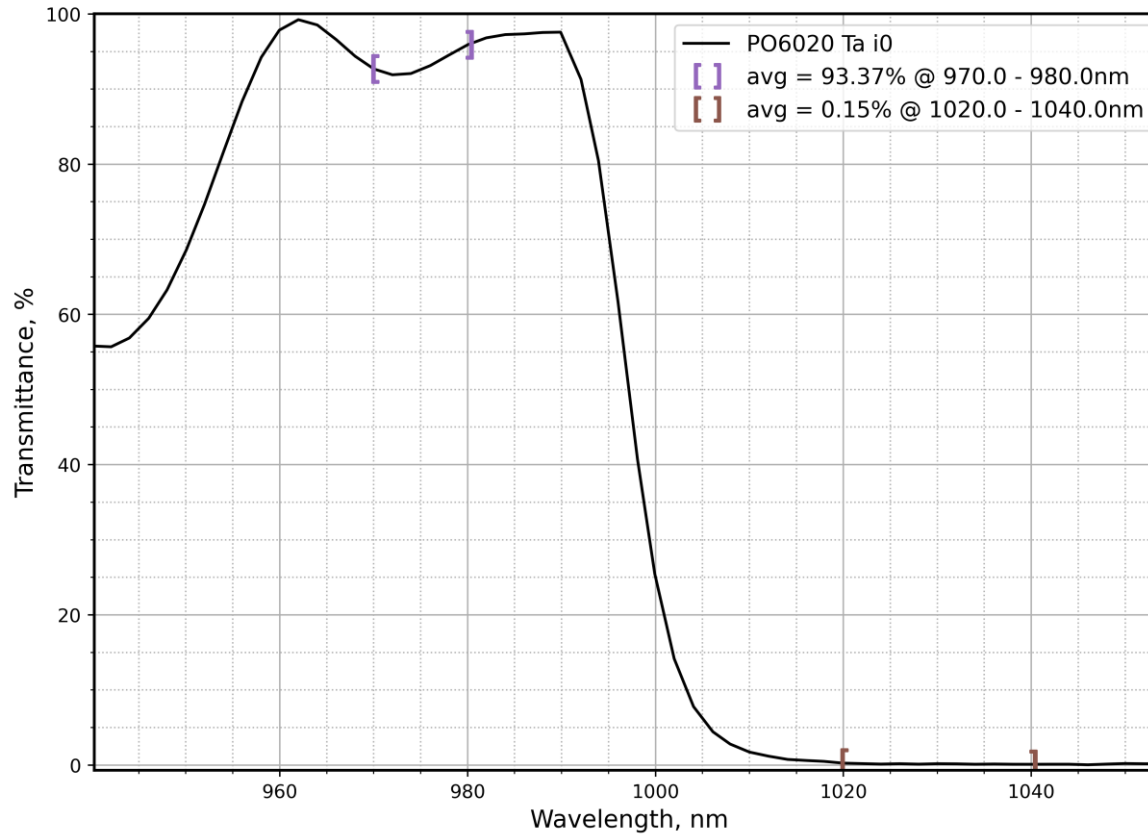


S1: HRsp_avg > 99.85% @ 1020 - 1040 nm + HTu > 97% 970 - 980 nm, AOI = 0-10 deg
 S2: ARu < 0.1% @ 970 - 980 nm, AOI = 0-10 deg



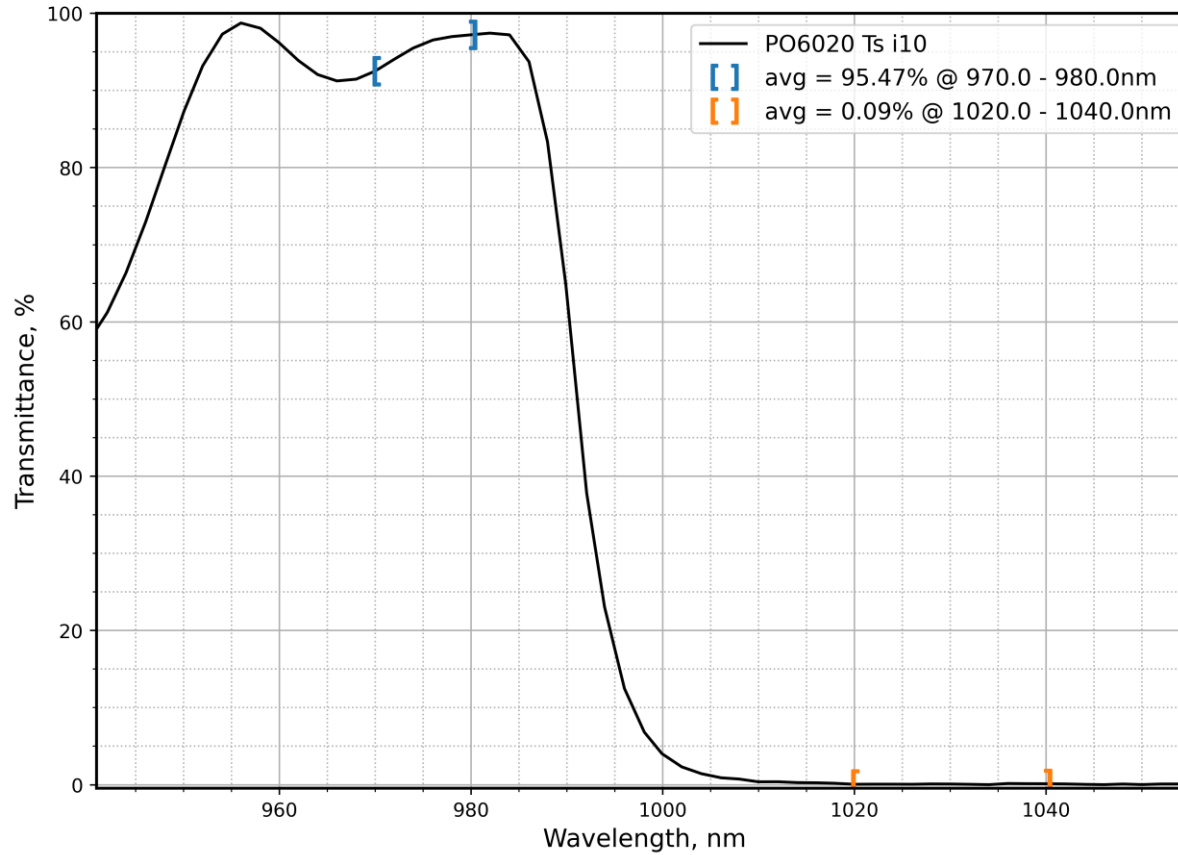
PO6020 Ta i0

Fig. 1.

SIDE MEASURED: S1+S2 (good component)

COMMENTS: Margin of measurement error: +/-0.25%

S1: HRsp_avg > 99.85% @ 1020 - 1040 nm + HTu > 97% 970 - 980 nm, AOI = 0-10 deg
 S2: ARu < 0.1% @ 970 - 980 nm, AOI = 0-10 deg



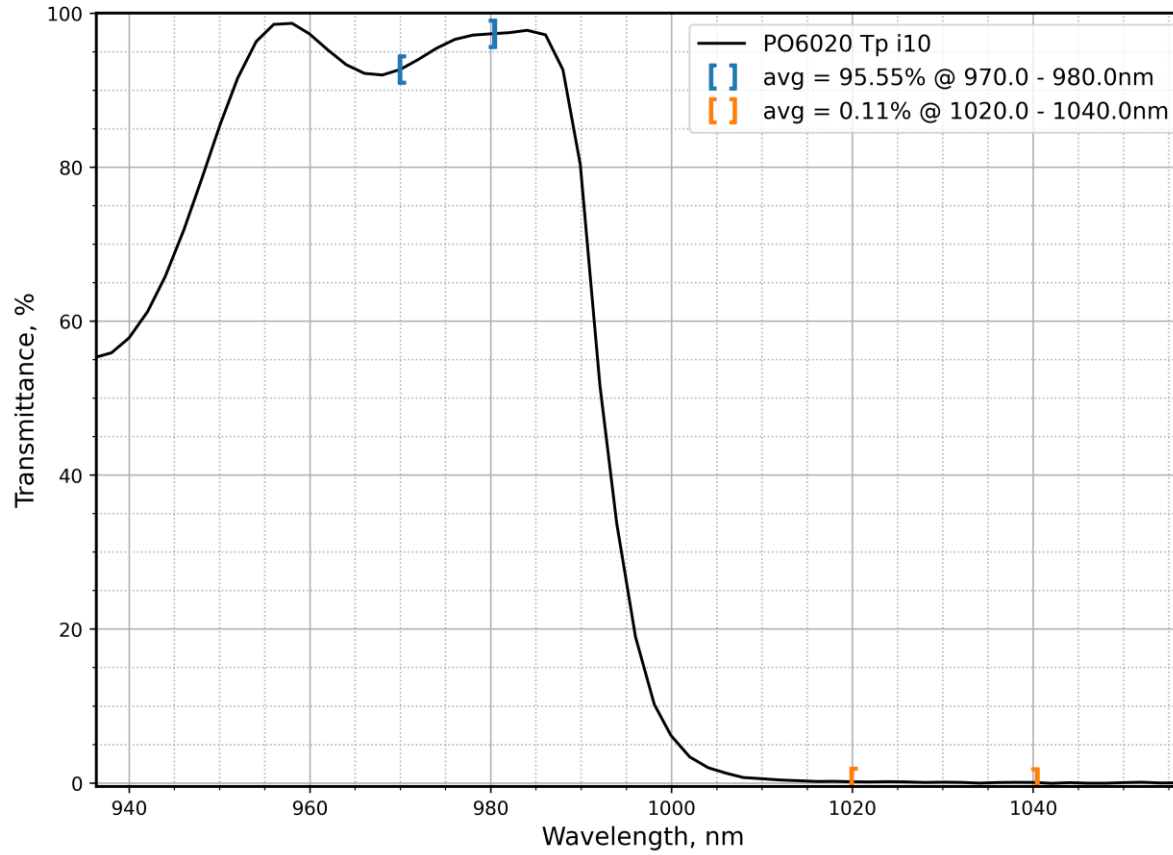
PO6020 Ts i10

Fig. 2.

SIDE MEASURED: S1+S2 (good component)

COMMENTS: Margin of measurement error: +/-0.25%

S1: HRsp_avg > 99.85% @ 1020 - 1040 nm + HTu > 97% 970 - 980 nm, AOI = 0-10 deg
 S2: ARu < 0.1% @ 970 - 980 nm, AOI = 0-10 deg



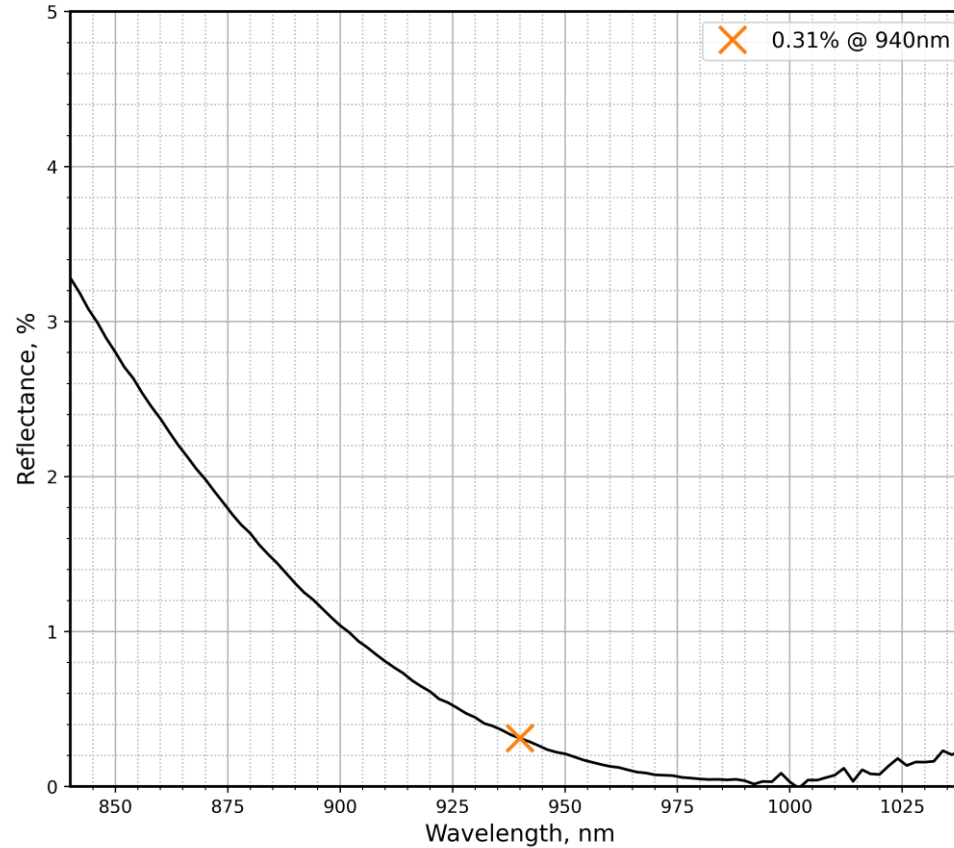
PO6020 Tp i10

Fig. 3.

SIDE MEASURED: S1+S2 (good component)

COMMENTS: Margin of measurement error: +/-0.25%

S1: (arrow marks) HRsp_avg > 99.9% @ 1020 - 1040 nm + HTu > 98% 940 nm, AOI = 0-10 deg
S2: ARu < 0.1% @ 940 + 980 nm, AOI = 0-10 deg



PO5206 Ra i10 S2 mat pvz

Fig. 4.

SIDE MEASURED: S2 only (grinded witness sample)

COMMENTS: Margin of measurement error: +/- 0.25%